


# PRODUCT / PROCESS CHANGE NOTIFICATION

## 1. PCN basic data

1.1 Company		STMicroelectronics International N.V
1.2 PCN No.	ADG/19/11644	
1.3 Title of PCN	HiQuad-64: Assembly Flow Improvement	
1.4 Product Category	see list	
1.5 Issue date	2019-07-24	

## 2. PCN Team

2.1 Contact supplier	
2.1.1 Name	ROBERTSON HEATHER
2.1.2 Phone	+1 8475853058
2.1.3 Email	heather.robertson@st.com
2.2 Change responsibility	
2.2.1 Product Manager	Elena Maria PERNIGOTTI,Fabrizio CASSANI,Giovanni FOLETTTO
2.1.2 Marketing Manager	Alberto DA DALT,Alberto CAROLI
2.1.3 Quality Manager	Marcello Donato MENCHISE

## 3. Change

3.1 Category	3.2 Type of change	3.3 Manufacturing Location
Methods	Process flow chart: Revision change in Process like addition, deletion of process step	ST Muar (Malaysia)

## 4. Description of change

	Old	New
4.1 Description	1st Crop after Plating	1st Crop before Deflash and Plating
4.2 Anticipated Impact on form,fit, function, quality, reliability or processability?	No impact	

## 5. Reason / motivation for change

5.1 Motivation	Quality Improvement. Minimization of solder residue
5.2 Customer Benefit	QUALITY IMPROVEMENT

## 6. Marking of parts / traceability of change

6.1 Description	Date code
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## 7. Timing / schedule

7.1 Date of qualification results	2019-06-24
7.2 Intended start of delivery	2020-01-01
7.3 Qualification sample available?	Upon Request

## 8. Qualification / Validation

8.1 Description	11644 Validation.pdf		
8.2 Qualification report and qualification results	Available (see attachment)	Issue Date	2019-07-24

## 9. Attachments (additional documentations)

11644 Public product.pdf 11644 Validation.pdf 11644 Details.pdf
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10. Affected parts		
10. 1 Current		10.2 New (if applicable)
10.1.1 Customer Part No	10.1.2 Supplier Part No	10.1.2 Supplier Part No
	E-TDA7570	
	L9779WD-SPI	
	L9779WD-SPI-TR	

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## Public Products List

Public Products are off the shelf products. They are not dedicated to specific customers, they are available through ST Sales team, or Distributors, and visible on ST.com

**PCN Title :** HiQuad-64: Assembly Flow Improvement

**PCN Reference :** ADG/19/11644

**Subject :** Public Products List

Dear Customer,

Please find below the Standard Public Products List impacted by the change.

L9779WD-TR	L9805E	L9779WD
L9779WD-SPI-TR	L9779WD-SPI	



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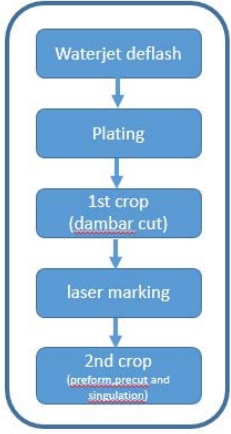
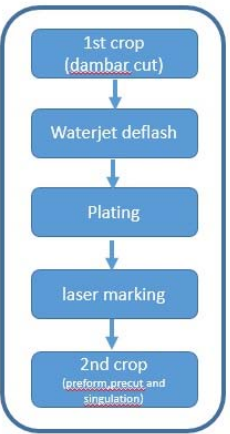
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## PRODUCT/PROCESS CHANGE NOTIFICATION

<b>SUBJECT</b>	<b>HI-QUAD 64: Assembly Flow Improvement</b>
<b>IMPACTED PRODUCTS</b>	All products housed in HI-QUAD 64 Leads 14x14
<b>MANUFACTURING STEP</b>	Assembly
<b>INVOLVED PLANT</b>	ST Muar Plant (Malaysia)
<b>CHANGE REASON</b>	Quality Improvement
<b>CHANGE DESCRIPTION</b>	<p>Optimization of process flow will be implemented as per below. New flow will minimize solder residue</p> <div style="display: flex; justify-content: space-around; align-items: flex-start;"> <div style="text-align: center;"> <p>Current</p>  <pre> graph TD     A[Waterjet deflash] --&gt; B[Plating]     B --&gt; C["1st crop (dambar cut)"]     C --&gt; D[laser marking]     D --&gt; E["2nd crop (preform, precut and singulation)"]           </pre> </div> <div style="text-align: center;"> <p>New</p>  <pre> graph TD     A["1st crop (dambar cut)"] --&gt; B[Waterjet deflash]     B --&gt; C[Plating]     C --&gt; D[laser marking]     D --&gt; E["2nd crop (preform, precut and singulation)"]           </pre> </div> </div>
<b>TRACEABILITY</b>	Internal traceability

## VALIDATION

Change as per ZVEI is classified as SEMPA-17.

ID	Type of change	No	Yes	
	ANY			
	DATA SHEET			
	DESIGN			
	PROCESS - WAFER PRODUCTION			
	BARE DIE			
	PROCESS - ASSEMBLY			
SEMPA-17	Change of specified assembly process sequence (deletion and/or additional process step)	---	P	[---]: no influence in final product integrity or specified sequence (P): influence in final product integrity or specified sequence [---]: e.g. additional cleaning step e.g. deletion of optical inspection (P): e.g. change lead finishing pre trim & form to post trim & form
	PACKING/SHIPPING			
	EQUIPMENT			
	TEST FLOW			
	Q-GATE			

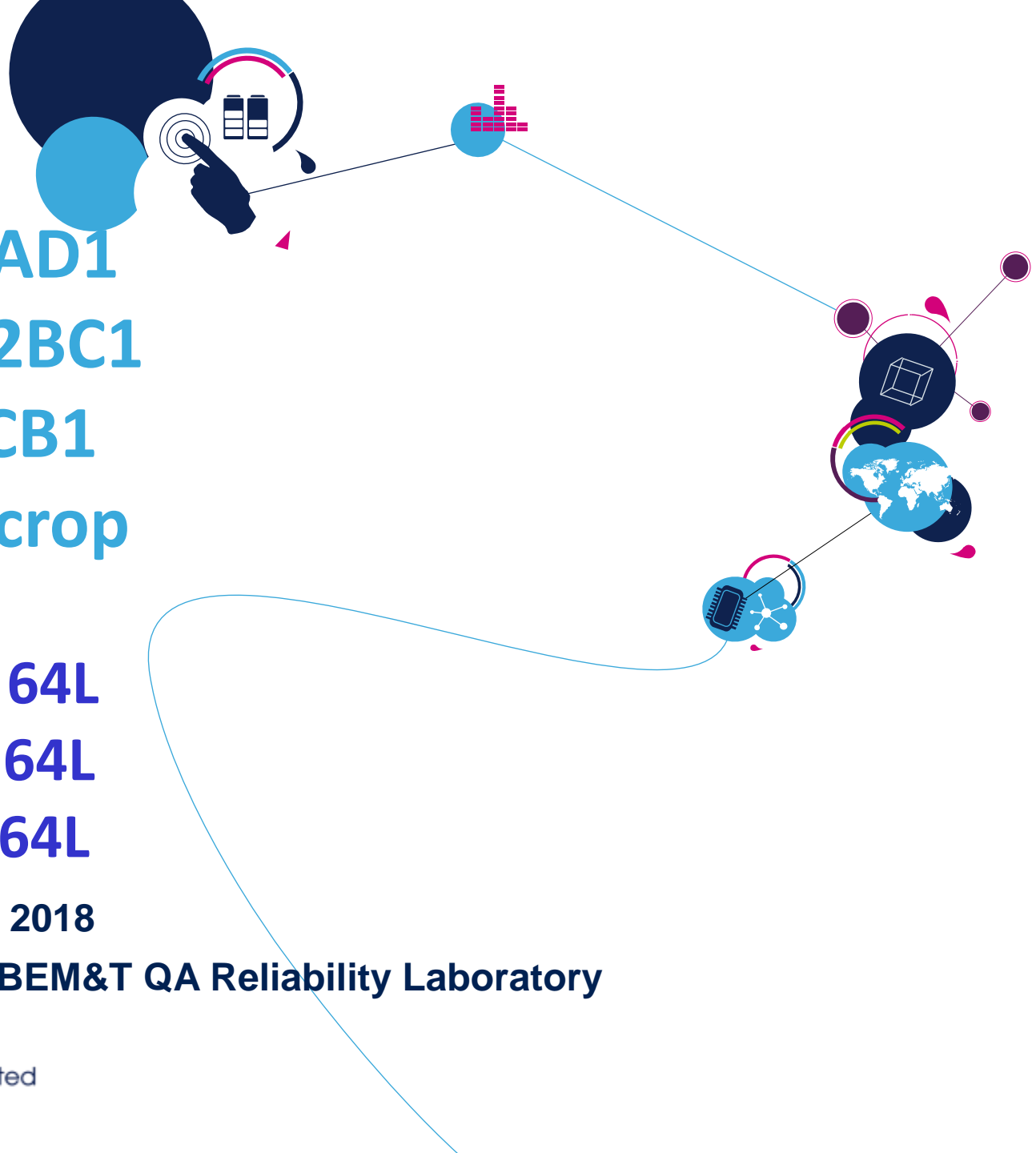
Trials have been executed according to AEC-Q100 see enclosed report

## REPORTS

11644 Validation.pdf

## IMPLEMENTATION

We are ready to implement the change upon Customer agreement from January 2020



**A99M\*UG30AD1**

**G99M\*UA412BC1**

**A69M\*UT60CB1**

**PCMS 2 step crop**

**UG30 – Hiquad 64L**

**UA41 – Hiquad 64L**

**UT60 – Hiquad 64L**

**Updated : 27<sup>th</sup> June 2018**

**Prepared By: Muar BEM&T QA Reliability Laboratory**



Note: Sampling 154 pcs/lot – taken from tested good units after FT.

2

Reliability Test Status								
No	Test Name	Prec	Condition/ Method	Steps	Steps	Fails/SS		Notes
						UG30 998041MFRR	UT60 9980417YRR	
1	PC (JL3 STD)		Bake 24 hrs @ 125°C Soak 192 hrs @ 30°C / 60% RH Reflow Profile = J-STD-020D (Tmax = 260°C)	Final	TSAM (0hr)	0 delam / 40 pcs	0 delam / 40 pcs	
					CSAM TOP (0hr)	0 delam / 40 pcs	0 delam / 40 pcs	
					ATE	0 def / 154 pcs	0 def / 154 pcs	
					TSAM	0 delam / 40 pcs	0 delam / 40 pcs	
					CSAM TOP	0 delam / 40 pcs	0 delam / 40 pcs	
2	TC	Yes	TA = -65°C / +150°C	1000 Cycle	ATE	0 def / 77 pcs	0 def / 77 pcs	
					TSAM	0 delam / 20 pcs	0 delam / 20 pcs	
					CSAM TOP	0 delam / 20 pcs	0 delam / 20 pcs	
3	Env Seq	Yes	TA = -65°C / +150°C PPT 121°C/ 2Atm	100TC 96 hrs	ATE	0 def / 77 pcs	0 def / 77 pcs	
					TSAM	0 delam / 20 pcs	0 delam / 20 pcs	
					CSAM TOP	0 delam / 20 pcs	0 delam / 20 pcs	

Note: Sampling 154 pcs/lot – taken from tested good units after FT.

3

Reliability Test Status									
No	Test Name	Pre c	Condition/ Method	Steps	Steps	Fails/SS			Notes
						UA41 998041DMRQ	UA41 998041DMRN	UA41 998041DMRR	
1	PC (JL3 STD)		Bake 24 hrs @ 125°C Soak 192 hrs @ 30°C / 60% RH Reflow Profile = J-STD-020D (Tmax = 260°C)	Final	TSAM (0hr)	0 delam / 40 pcs	0 delam / 40 pcs	0 delam / 40 pcs	
					CSAM TOP (0hr)	0 delam / 40 pcs	0 delam / 40 pcs	0 delam / 40 pcs	
					ATE	0 def / 154 pcs	0 def / 154 pcs	0 def / 154 pcs	
					TSAM	0 delam / 40 pcs	0 delam / 40 pcs	0 delam / 40 pcs	
					CSAM TOP	0 delam / 40 pcs	0 delam / 40 pcs	0 delam / 40 pcs	
2	TC	Yes	TA = -65°C / +150°C	1000 Cycle	ATE	0 def / 77 pcs	0 def / 77 pcs	0 def / 77 pcs	
					TSAM	0 delam / 20 pcs	0 delam / 20 pcs	0 delam / 20 pcs	
					CSAM TOP	0 delam / 20 pcs	0 delam / 20 pcs	0 delam / 20 pcs	
3	Env Seq	Yes	TA = -65°C / +150°C PPT 121°C/ 2Atm	100TC 96 hrs	ATE	0 def / 77 pcs	0 def / 77 pcs	0 def / 77 pcs	
					TSAM	0 delam / 20 pcs	0 delam / 20 pcs	0 delam / 20 pcs	
					CSAM TOP	0 delam / 20 pcs	0 delam / 20 pcs	0 delam / 20 pcs	

A99M\*UG30AD1 : Lot ID 998041MFRR

TSAM (Thru Scan) CSAM (Die Top) @ T0



TSAM



CSAM Top

Unit Position From 1 - 60

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

A99M\*UG30AD1 : Lot ID 998041MFRR

TSAM (Thru Scan) CSAM (Die Top) @ after JL3



TSAM



CSAM Top

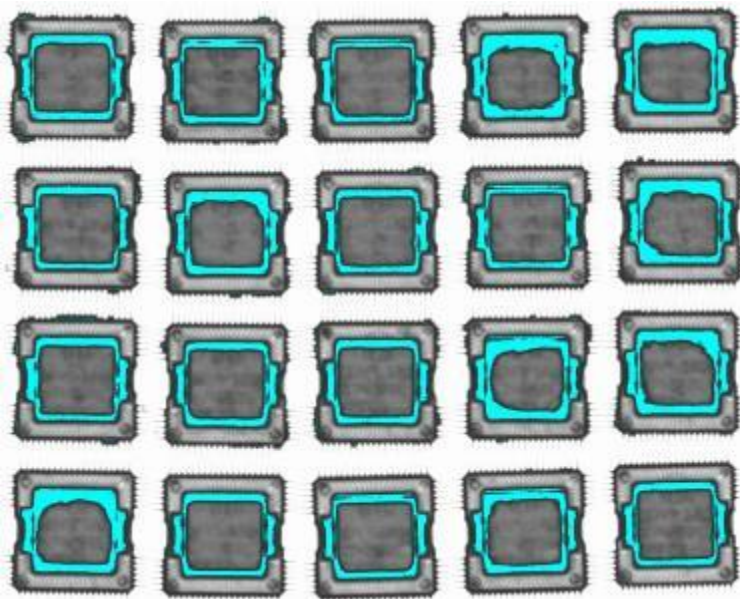
## Unit Position From 1 - 40

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

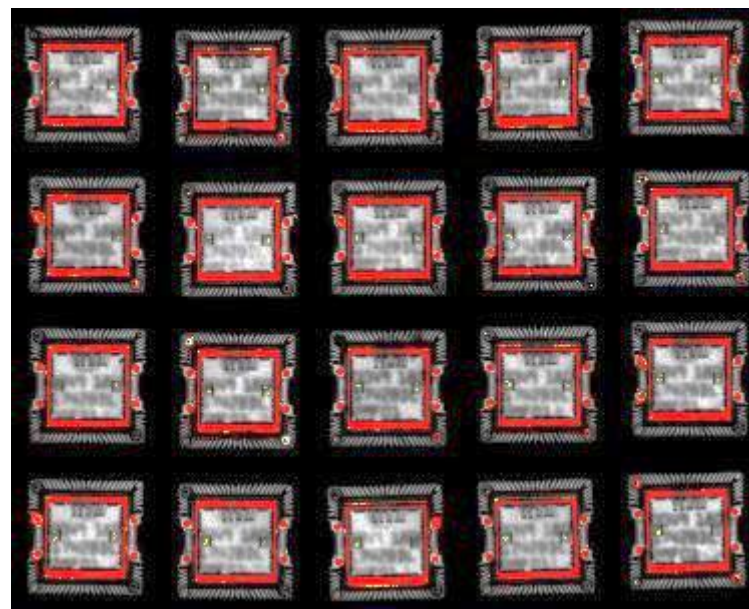


A99M\*UG30AD1 : Lot ID 998041MFRR

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 1000TC



TSAM



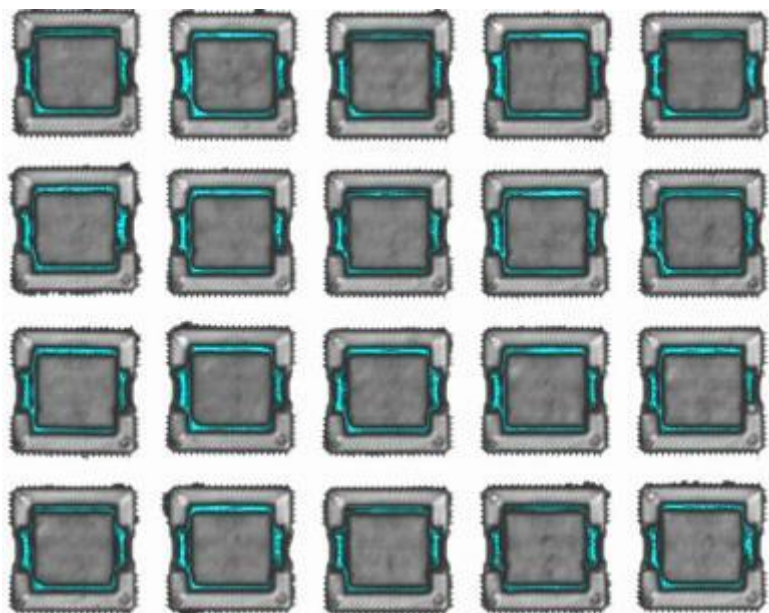
CSAM Top

## Unit Position From 1 - 20

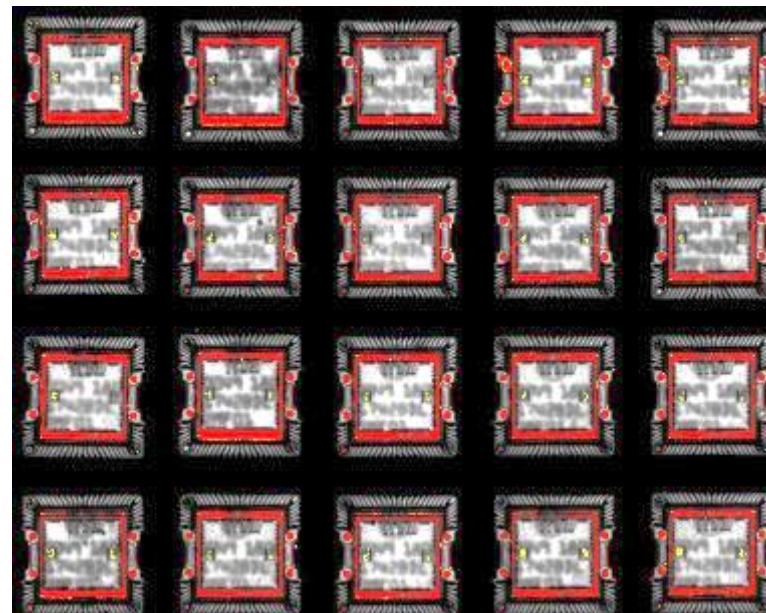
Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

A99M\*UG30AD1 : Lot ID 998041MFRR

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 100TC + PPT 96 hrs



TSAM



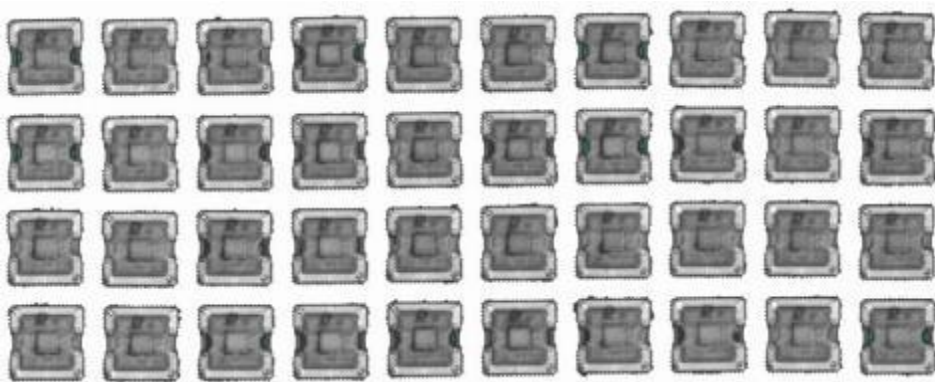
CSAM Top

## Unit Position From 21 - 40

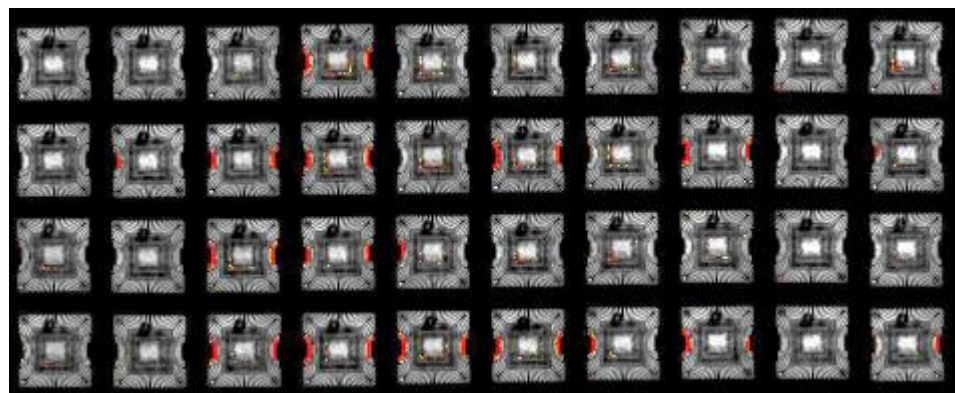
Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

A69M\*UT60CB1 : Lot ID 9980417YRR

TSAM (Thru Scan) CSAM (Die Top) @ T0



TSAM



CSAM Top

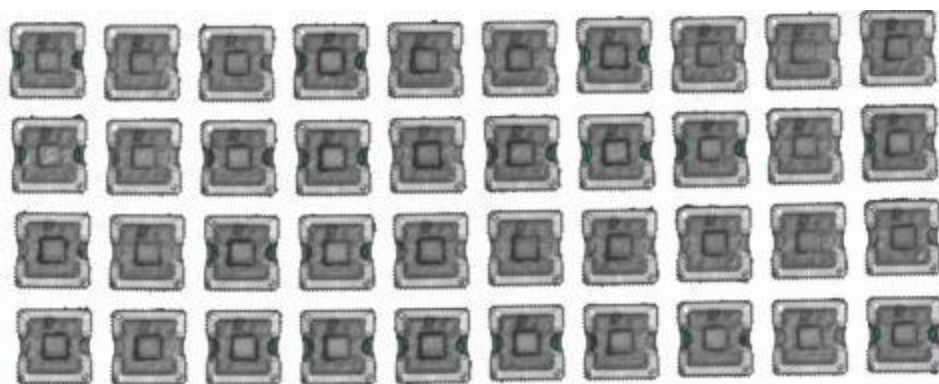
Unit Position From 1 - 60

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

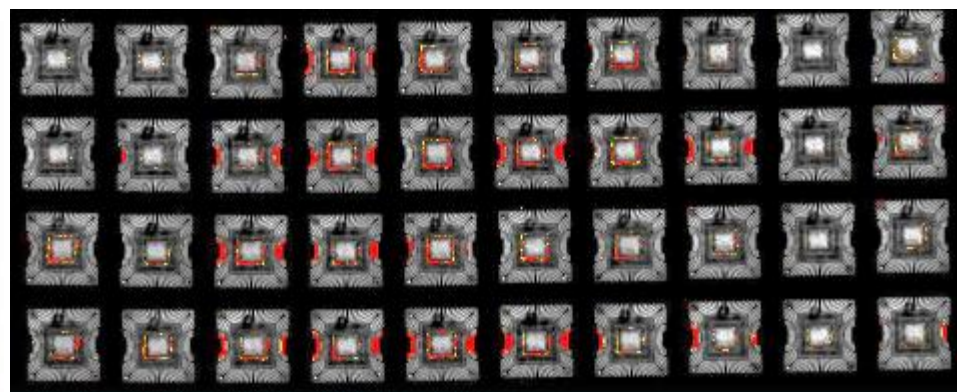


A69M\*UT60CB1 : Lot ID 9980417YRR

TSAM (Thru Scan) CSAM (Die Top) @ after JL3



TSAM



CSAM Top

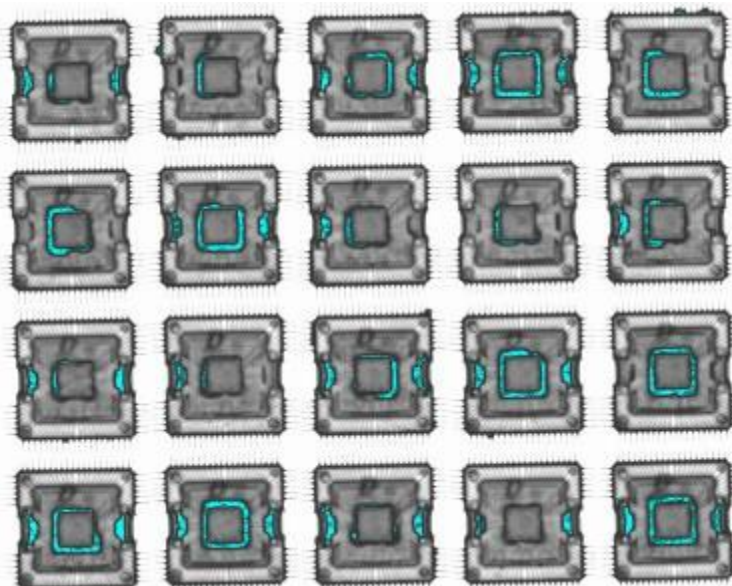
Unit Position From 1 - 40

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

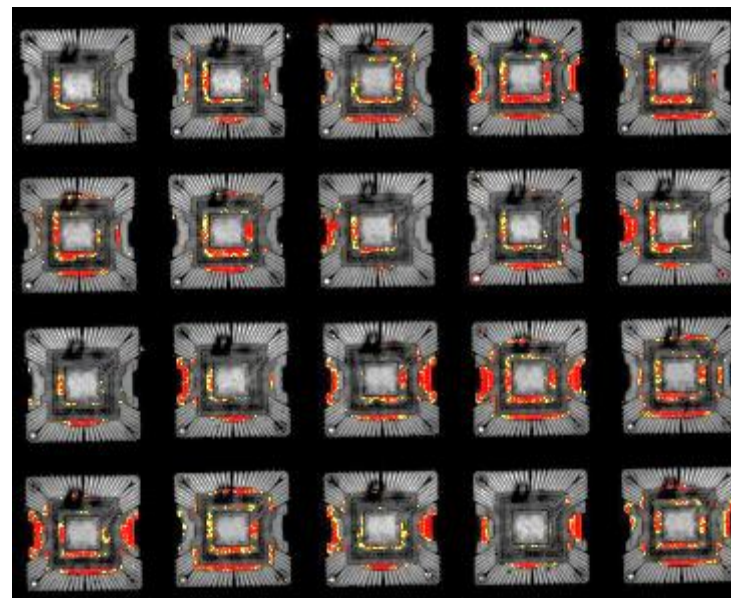


A69M\*UT60CB1 : Lot ID 9980417YRR

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 1000TC



TSAM



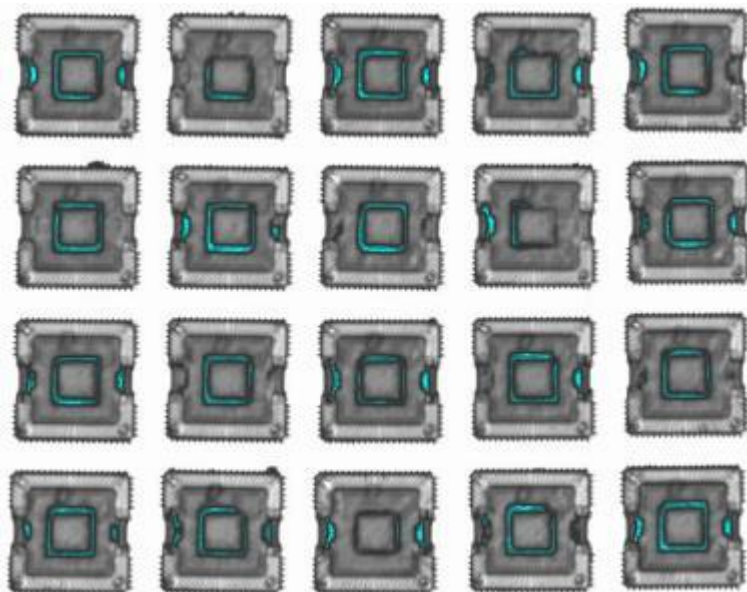
CSAM Top

## Unit Position From 1 - 20

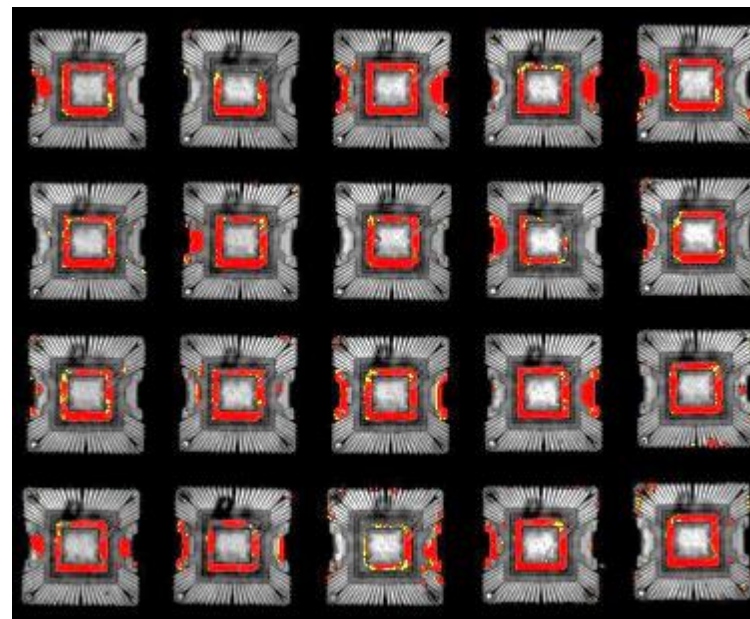
Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

A69M\*UT60CB1 : Lot ID 9980417YRR

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 100TC + PPT 96 hrs



TSAM



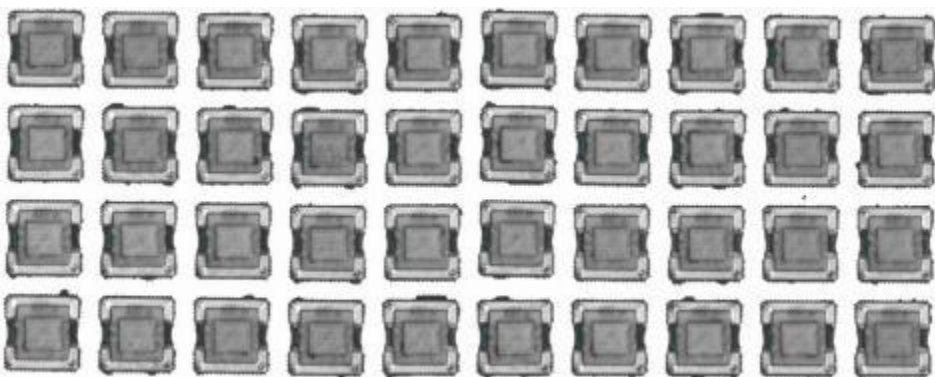
CSAM Top

## Unit Position From 21 - 40

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

G99M\*UA412BC1 : Lot ID 998041DMRQ

TSAM (Thru Scan) CSAM (Die Top) @ T0



TSAM



CSAM Top

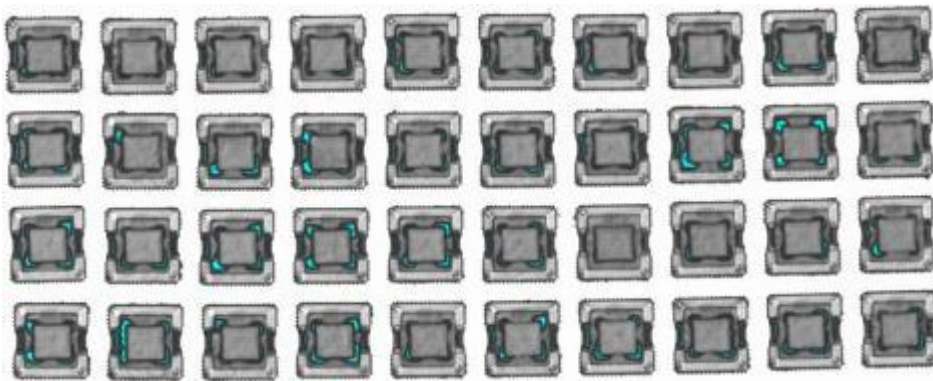
Unit Position From 1 - 60

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass



G99M\*UA412BC1 : Lot ID 998041DMRQ

TSAM (Thru Scan) CSAM (Die Top) @ after JL3



TSAM



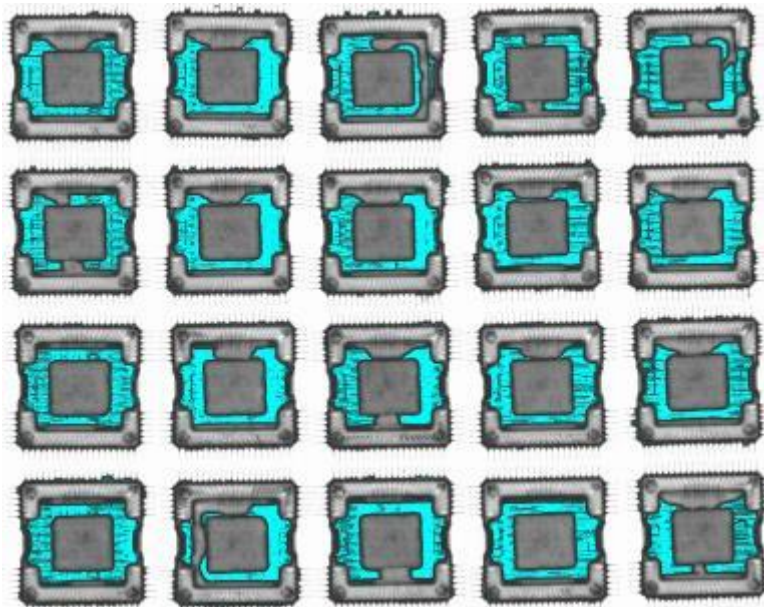
CSAM Top

Unit Position From 1 - 40

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

G99M\*UA412BC1 : Lot ID 998041DMRQ

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 1000TC



TSAM



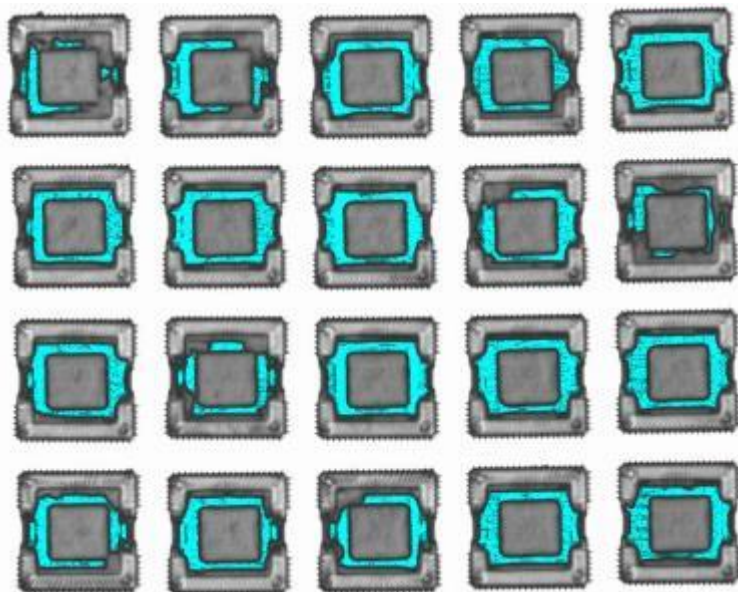
CSAM Top

## Unit Position From 1 - 20

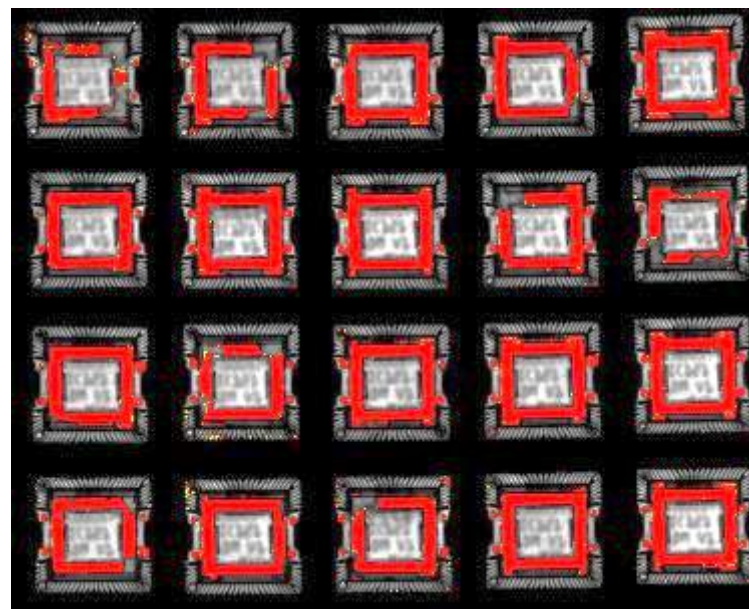
Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

G99M\*UA412BC1 : Lot ID 998041DMRQ

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 100TC + PPT 96 hrs



TSAM



CSAM Top

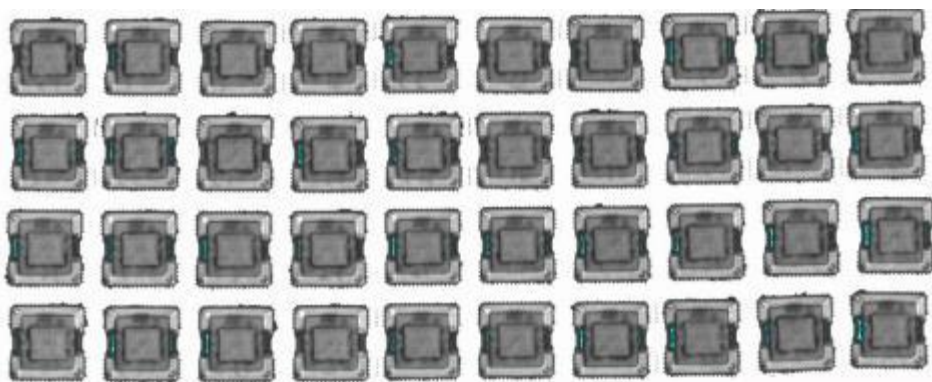
## Unit Position From 21 - 40

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass



G99M\*UA412BC1 : Lot ID 998041DMRN

TSAM (Thru Scan) CSAM (Die Top) @ T0



TSAM



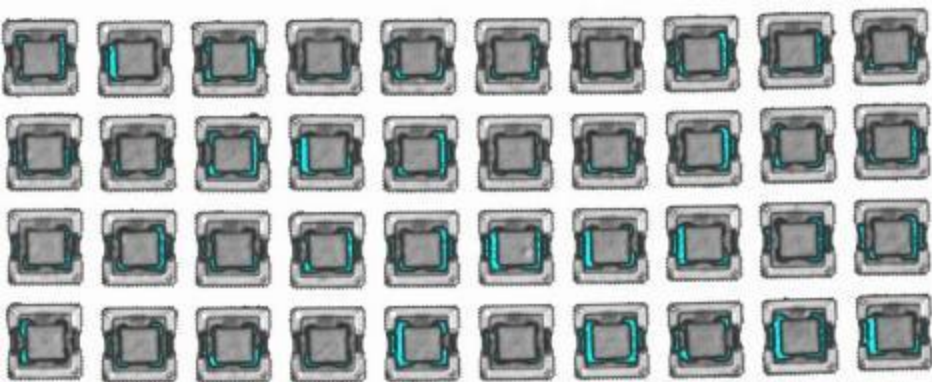
CSAM Top

Unit Position From 1 - 60

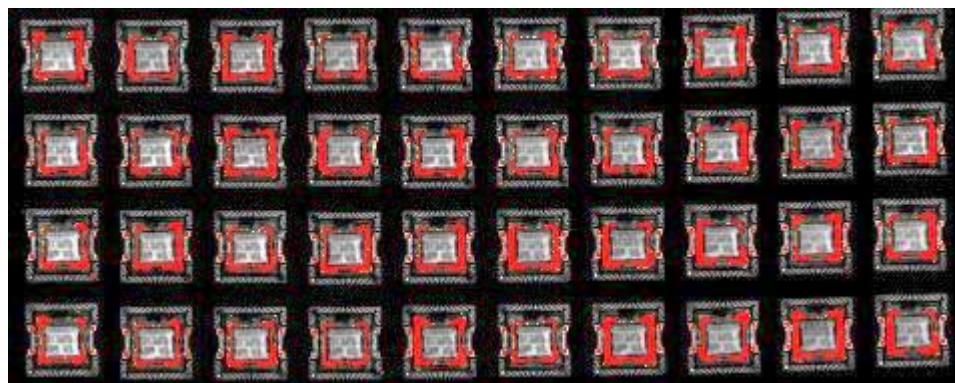
Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

G99M\*UA412BC1 : Lot ID 998041DMRN

TSAM (Thru Scan) CSAM (Die Top) @ after JL3



TSAM



CSAM Top

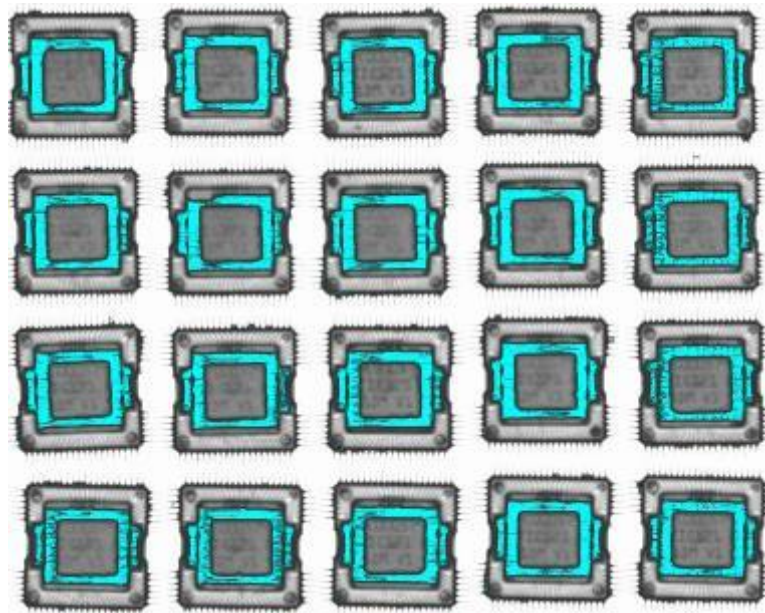
## Unit Position From 1 - 40

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

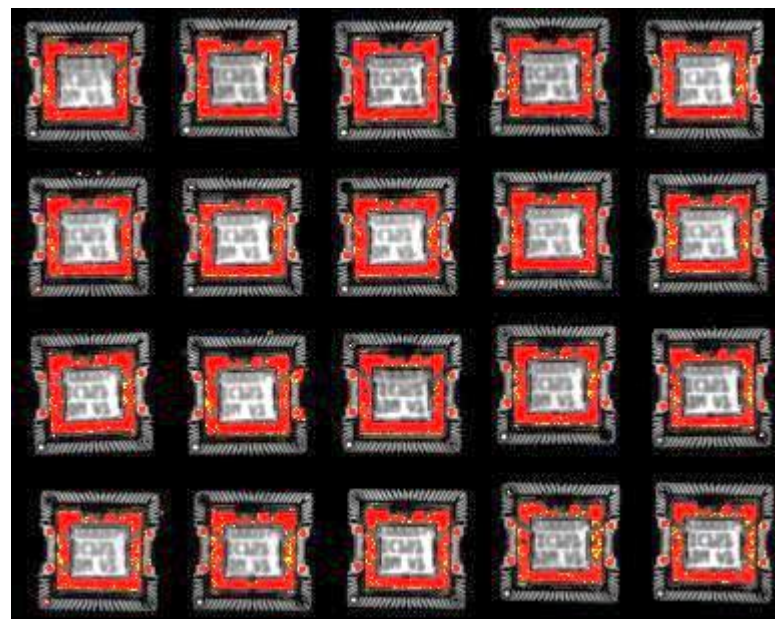


G99M\*UA412BC1 : Lot ID 998041DMRN

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 1000TC



TSAM



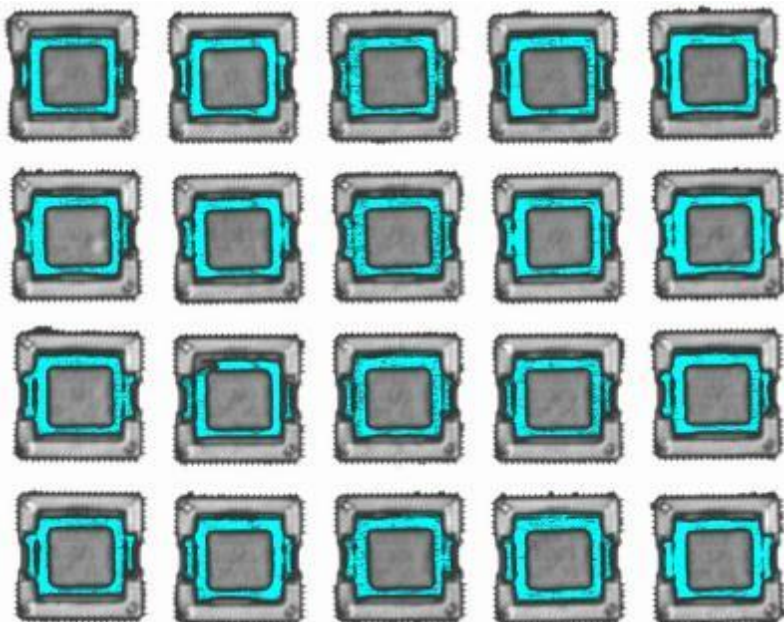
CSAM Top

## Unit Position From 1 - 20

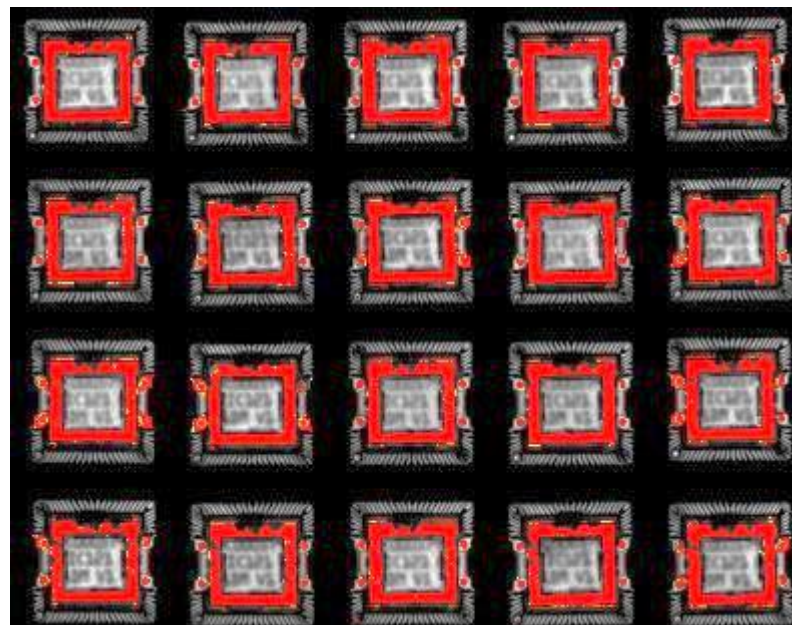
Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

G99M\*UA412BC1 : Lot ID 998041DMRN

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 100TC + PPT 96 hrs



TSAM



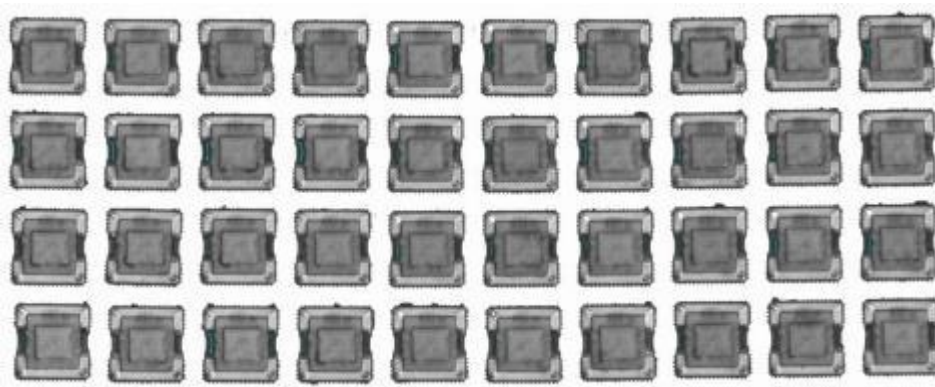
CSAM Top

## Unit Position From 21 - 40

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

G99M\*UA412BC1 : Lot ID 998041DMRR

TSAM (Thru Scan) CSAM (Die Top) @ T0



TSAM



CSAM Top

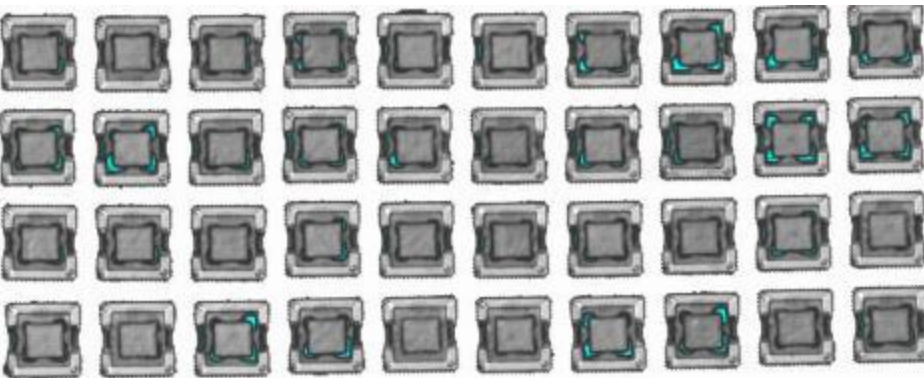
Unit Position From 1 - 60

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass



G99M\*UA412BC1 : Lot ID 998041DMRR

TSAM (Thru Scan) CSAM (Die Top) @ after JL3



TSAM



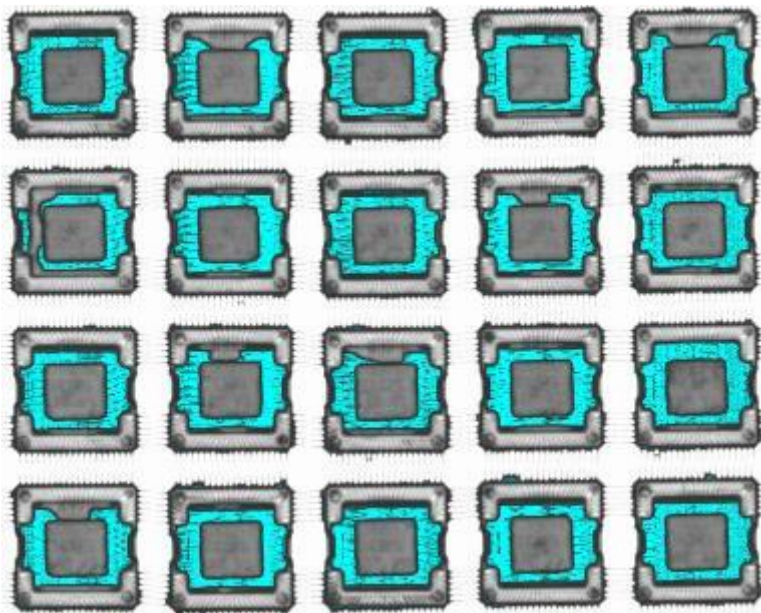
CSAM Top

Unit Position From 1 - 40

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

G99M\*UA412BC1 : Lot ID 998041DMRR

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 1000TC



TSAM



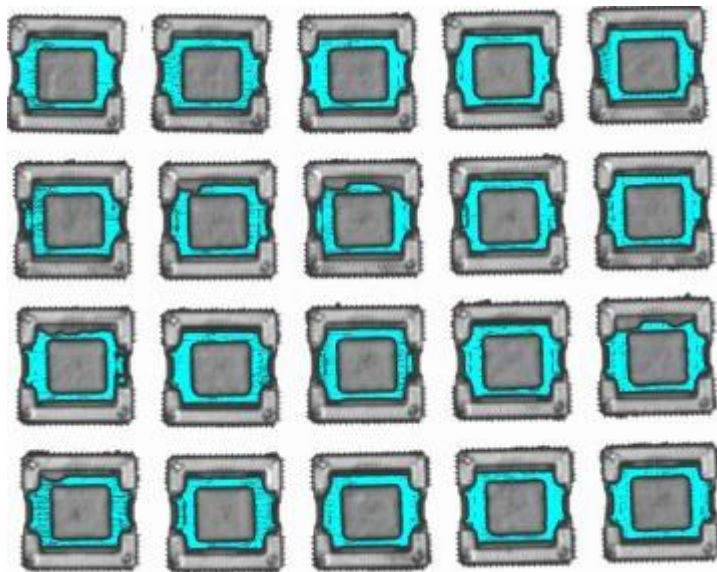
CSAM Top

## Unit Position From 1 - 20

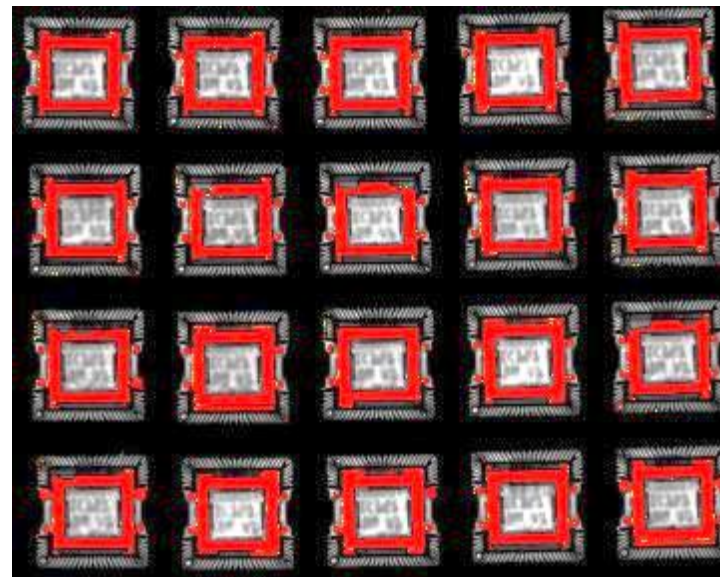
Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass

G99M\*UA412BC1 : Lot ID 998041DMRR

TSAM (Thru Scan) CSAM (Die Top) @ after JL3 + 100TC + PPT 96 hrs



TSAM



CSAM Top

## Unit Position From 21 - 40

Delamination interface	Spec 7512807
Die / molding compound	Pass
Die Attach Material	Pass
Die-pad / molding compound (front side)	Pass
Die-pad / molding compound (back side)	Pass



## Qualification Summary:

### ❑ Automatic Electrical Test (ATE):

- a. No any electrical failure detection after following reliability test steps (100% All Pass).
  - a.1. after preconditioning MSL3 (3X Reflow)
  - a.2. after 1000TC
  - a.3. after env seq Test (100TC + 96 hours PPT)

### ❑ Scanning Accoustic Microscopy (SAM):

- a. No Delamination on Die Attach Material (Glue Interface) at
  - a.1 Time-0
  - a.2 after MSL3 (3X Reflow).
  - a.3 after 1000TC
  - a.4 after env seq
- b. Die-pad front side / molding compound delam presence at Time-0 and start to propagates after MSL3 (3X reflow) & TC1000 cycles & env seq. Since UG30 / UA41 Hiquad 64L package with no ground bond, the delamination still acceptable as per ST Specs 7512807.